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Magnetic Tunnel Junction Sensors With Conetic Alloy

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Al₂O₃ magnetic tunneling junction (MTJ) sensors were fabricated with Conetic alloy Ni₇₇Fe₄Cu₆Mo₂ deposited as the free layer and pinned layer for its soft magnetic properties. It was observed that the Al₂O₃ MTJ sensors with Conetic exhibited relatively small easy-axis coercivity. Tunneling magnetoresistance (TMR) and noise measurements were carried out to characterize the sensors. TMR of 9.5% and Hooge parameter of 3,825 × 10⁻⁷ μm² were achieved without any hard-axis field. Hard-axis bias field was applied to eliminate the hysteresis and improve the linear field response of the MTJ sensor. The hysteresis was removed by applying an external magnetic field along the hard axis at 8 Oe and the sensor sensitivity was 0.4 %/Oe within a linear region at room temperature. The relationship between the Hooge parameter and hard-axis field was also investigated and the result demonstrated that the 1/f noise can be suppressed by an optimized hard-axis bias field. This work shows that it is feasible to use Conetic alloy as the soft magnetic layers in MTJ sensors for its small coercivity, and a hard-axis bias field can be used to linearize the sensor response and suppress the 1/f noise.

Index Terms—1/f Noise, Conetic, hard-axis bias field, magnetic sensor, magnetic tunnel junction (MTJ).

I. INTRODUCTION

Magnetic tunnel junctions (MTJs) have drawn tremendous attentions for their applications in magnetic field sensors [1], hard disk drive (HDD) read heads [2], and magnetic random access memory (MRAM) [3], [4] due to their high tunneling magnetoresistance (TMR), low cost, and high sensitivity. MTJs with 1000% TMR [5] were theoretically predicted and 604% TMR [6] were experimentally demonstrated at room temperature. Thus MTJs are regarded as a promising candidate for ultra-low magnetic field detection.

However, hysteresis-free and linear field responses are needed for practical sensor applications and much effort has been paid for obtaining MTJs with small coercivity [7]–[12]. Previous work utilizing Conetic alloy exhibited large TMR and small saturation fields [12]. The Conetic alloy is the soft magnetic material NiFeCuMo of mu-metal family. They possess relatively small easy-axis coercivity (Hₑₑₑₑ ≈ 10⁻⁴ Oe) and large hard-axis magnetic susceptibility (χ ≈ 10⁴⁻⁵) in both single-film and synthetic antiferromagnet (SAF) multilayer configurations [11], [13]. These magnetic properties of Conetic thin films are close to those of the corresponding bulk material [14]. Hence, Conetic alloy is a competent alternative magnetic thin film of MTJ stacks for ultra-low magnetic field detection.

Another limiting factor of MTJ sensitivity is intrinsic noise problem, especially in the low-frequency regime. It is because the ultimate detectivity of a sensor is determined by the noise floor at the operating point. The dominant noise source in MTJs is 1/f noise in the low-frequency regime which can be parameterized by the Hooge parameter [15]

\[ \alpha = \frac{A f}{V_s^2} \]  

where \( A \) is the junction area, \( f \) is the frequency, \( S \) is the voltage power of 1/f noise, and \( V_s \) is the voltage across the junction. The 1/f noise was reported to originate from both electrical mechanism (charge trapping of electrons in the tunneling barriers) and magnetic mechanism (magnetization fluctuations in the magnetic layers), and it deteriorates the sensitivity of MTJs in low-frequency sensing applications [16]–[21]. Therefore, in order to realize ultrasensitive magnetic field sensors, the MTJs must possess large TMR, low saturation field, low noise, and linear response [22].

In this work, Conetic was deposited as the magnetic free layer and the pinned layer of the MTJs for its soft magnetic properties and small coercivity. Both TMR and noise measurements were carried out. Hard-axis bias field was used to eliminate hysteresis and obtain linear-field response. The relationship between the Hooge parameter and hard-axis bias field was also investigated.

II. EXPERIMENT

The MTJ stack structure was substrate/ Ni₇₇Fe₄Cu₆Mo₂ 200/ Co₉₀Fe₵₀ 10 / Al 10, plasma oxidation, O₂ = 10⁻³ Torr, / Co₇₀Fe₃₀ 10/ Ni₇₇Fe₄Cu₆Mo₄ 25/ Co₉₀Fe₵₀ 5/ Ir₃₀Mn₸₀ 100/ Ru 70 (units in angstrom), as shown in Fig. 1(a). The thin films were deposited by dc magnetron sputtering on thermally oxidized silicon wafers in an ultra-high vacuum chamber with a base pressure of 2 × 10⁻¹⁰ Torr. The Al₂O₃ barrier layer was made by first depositing Al metal and then oxidizing it in oxygen plasma. The sample was annealed at 200°C for 15 min. The junctions were fabricated by self-aligned UV photolithography and etching processes with the junction area of 20 × 20 μm². Four-probe electrical measurement was performed with 50 μA dc current. Two pairs of Helmholtz coils, one along the easy-axis and another along the hard-axis, were used to provide magnetic field ranging from −200 Oe to +200 Oe. The noise measurement was carried out in a Wheatstone bridge configuration to reduce the effect of thermal drift and dc offset. The Helmholtz coils and bridge circuit are shielded in a mu-metal shielding box. A low-noise low-frequency instrumentation preamplifier (FEMTO DLPVA-100-BLN-S) with a gain of 40 dB is equipped to amplify the output signal from the bridge.
circuit. The schematic diagram of the noise measuring circuit is shown in Fig. 1(b). Noise power spectrum of the sample was detected by a dual-channel spectrum analyzer (Stanford Research SR785) with cross-correlation mode to effectively reduce the background noise floor of the measuring system. All the measurements were performed at room temperature.

III. RESULT AND DISCUSSION

Fig. 2 shows the TMR and noise measurement results with an external magnetic field applied along the easy-axis in absence of any hard-axis bias field. The TMR ratio is 9.5% and the value of $\alpha$ is $3.825 \times 10^{-7} \mu m^2$ calculated by (1). The easy-axis coercivity is $\sim 3$ Oe. A hard axis bias field was subsequently applied to remove the hysteresis. The influence of the hard-axis bias field on the TMR transfer curves is presented in Fig. 3. As the hard-axis bias field increased from 2 Oe to 20 Oe, the hysteresis reduced and it was eliminated at 8 Oe. The sensitivity of the MTJ sensor under this configuration was found to be 0.4%/Oe from the slope of the transfer curve at low field. Further increase of the hard-axis bias field from 8 Oe to 20 Oe made the slope of the transfer curve less steep and thus reduced the sensor sensitivity. The elimination of hysteresis can be interpreted by Stoner-Wohlfarth (SW) model [23].

Our results are compared with some previous works on Al$_2$O$_3$ MTJs without Conetic alloy. Tondra et al. [1] showed MTJs with 20% TMR ratio and they used 20 Oe hard-axis field to reduce the hysteresis of the MR curve. Liu et al. [9] achieved MTJs with 35% TMR ratio and applied less than 10 Oe hard-axis field to eliminate the hysteresis. Nowak et al. [16] reported MTJs with 35% TMR and Hooge parameter of $10^{-7}$–$10^{-6} \mu m^2$. Nor et al. [18] obtained MTJs with 19.5% TMR and Hooge parameter of $10^{-6}$–$10^{-5} \mu m^2$. Compared with these results, although the Al$_2$O$_3$ MTJ sensors with Conetic alloy have small TMR ratios, they exhibit relatively small coercivity (hysteresis was removed with only 8 Oe hard-axis field) while retaining a moderate $\alpha$ for the $1/f$ noise. This indicates that Conetic alloy is effective for reducing the magnetostriiction constant and magnetocrystalline anisotropy while retaining a moderate noise level. However, more work should be done in the future to enhance the TMR ratio for improving the MTJ sensor performance.

After the eradication of hysteresis in the MTJs, noise measurement was performed over a range of hard-axis bias field. Fig. 4 shows the measurement results of the Hooge parameter versus the hard-axis field. Below 60 Oe, the Hooge parameter decreases with the hard-axis bias field and it decreases to $3.567 \times 10^{-7} \mu m^2$ at 60 Oe. This indicates the $1/f$ noise has a magnetic-field dependent component and it can be reduced by applying hard-axis field. The decline of magnetic $1/f$ noise was attributed to the reduction of thermally magnetic fluctuations provoked by hopping of domain walls in the metastable free layer of MTJs [20], [21], [24], [25]. When the hard-axis field is applied, the domains of the free layer start to be aligned and they overcome the thermal energy to avoid the thermally induced hopping response. With the increase of the hard-axis biasing field, the number of aligned magnetization domains increases. At 60 Oe, the Hooge parameter reached a minimum value. In order to confirm that the decline of the Hooge parameter was resulted from the magnetic $1/f$ noise rather than the frequency-independent thermal magnetic noise, we carried out an analysis on the MTJ noise power based on the theoretical model published previously [22]. The calculation result shows that the noise power of thermal magnetic noise is around two orders of magnitude smaller than the magnetic $1/f$ noise and around three orders of magnitude smaller than the electronic $1/f$ noise at low-frequency regime. As such, when evaluating the Hooge parameter of our samples, the thermal magnetic noise was negligible compared with magnetic $1/f$ noise and electronic $1/f$ noise. Therefore, the decline of Hooge parameter below 60 Oe was most likely associated with the reduction of magnetic $1/f$ noise. Beyond 60 Oe, the Hooge parameter slowly increases as we can see from the right of the dash line in Fig. 4. This increase may be due to the magnetization rotation of the pinned layer of MTJs. Due to the large hard-axis bias field, the magnetization of the pinned layer changes slightly from its original pinned direction towards the hard axis. This leads to the change of the angle between the magnetization directions of the pinned layer and the free layer, resulting in a reduction of junction resistance. As such, the voltage across
Fig. 3. TMR loops of MTJs with different biasing fields along the hard-axis. From (a), (b), and (c), we can see the hysteresis reduced with the hard-axis bias field. (d) The hysteresis is removed at 8 Oe of hard-axis bias field and the sensor sensitivity is 0.4%/Oe. (e) and (f) show that further increase of hard-axis bias field reduces TMR and the slope of the linear region.

Fig. 4. Hooge parameter measurements at different hard-axis bias fields from 0 Oe to 130 Oe. The dash line is a guide for eyes. On the left of the dash line, the Hooge parameter decreases with the hard-axis field down to $3.587 \times 10^{-7} \mu \text{m}^2$ at the hard-axis bias field of 60 Oe. On the right of the dash line, the Hooge parameter increases with the hard-axis bias field up to $3.825 \times 10^{-7} \mu \text{m}^2$ at the hard-axis bias field of 130 Oe. The sharp decrease of the Hooge parameter from 0 Oe to 20 Oe of hard-axis bias field is elaborated with more detailed noise measurement in this range of hard-axis bias field as shown in the inset.

the junction decreases. Subsequently, the Hooge parameter increases with the decrease of junction voltage according to (1). These results are significant for MTJ sensing applications because it indicates that an optimized hard-axis bias field must be used in order to minimize the $1/f$ noise.

IV. CONCLUSION

We fabricated $\text{Al}_2\text{O}_3$ MTJs with Conetic alloy as the magnetic layers due to its soft magnetic properties. The MTJs exhibited TMR of 9.5% and coercivity of 3 Oe. A small value of coercivity is critical for the sensitivity of MTJ sensors. Noise measurement was carried out and the Hooge parameter was $3.825 \times 10^{-7} \mu \text{m}^2$ (without hard-axis bias field). These $\text{Al}_2\text{O}_3$ MTJ sensors with Conetic alloy have relatively small coercivity while retaining a moderate $c_t$. These results indicate that MTJ sensors with Conetic alloy are promising for further applications in low magnetic-field sensing because it does not deteriorate the $1/f$ noise and it has the advantage of having small coercivity. A hard-axis bias field of 8 Oe was applied to eliminate the hysteretic response and improve the linearity of the Conetic MTJ sensors. An optimized sensitivity of 0.4%/Oe was obtained. The noise measurement results over a range of hard-axis bias field demonstrate that the hard-axis bias field (<60 Oe) can reduce the $1/f$ noise level of MTJs while a hard-axis bias field larger than 60 Oe increases the $1/f$ noise. Therefore, a hard-axis bias field with an appropriate magnitude not only enables to eliminate the hysteretic response but also reduce the magnetically derived $1/f$ noise of the MTJ sensors.

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